			Application/Control No.	Applicant(s)/Patent Under Reexamination
Notice of References Cited			10/604,244	TAI ET AL.
			Examiner	Art Unit	Page 1 of 1
			Toan M. Le	2863	

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,618,682	09-2003	Bulaga et al.	702/84
	B	US-6,154,714	11-2000	Lepejian, David Yepejian	702/118
	C	US-6,477,685	11-2002	Lovelace, Jerome R.	716/4
	D	US-6,314,379	11-2001	Hu et al.	702/81
	E	US-6,613,590	09-2003	Simmons, Steven J.	438/14
	F	US-6,265,232	07-2001	Simmons, Steven J.	438/14
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Lee, J., Design of Intelligent Data sampling Methodology Based on Data Mining, October 2001, IEEE Transactions on Robotics and automation, Vol. 17, No. 5, Pages 637-649
	V	Mieno et al., Yield Improvement Using Data Mining System, 1999 IEEE, Pages 391-394
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.